Electronic Supplementary Information

Characterization Techniques

Fourier transformed Infrared (FTIR) spectra were recorded on a PerkinElmer, USA spectrometer using KBr pellets. X-ray diffraction (XRD) patterns were recorded by using by an X-ray diffractometer of Miniflex, Rigaku Corporation, Japan. UV-visible spectra were taken at room temperature using Thermo Scientific, USA photospectrometer. Elemental composition study was conducted by an electron dispersive X-ray (EDX) spectrometer of Oxford, JSM-6390LV. Raman spectra were recorded by a Raman spectrometer (Horiba Jobin Vyon, Model LabRam HR) using a laser source of wavelength 514 nm. The shape and size of HAp nanoparticles and their distribution were studied by using a high resolution transmission electron microscope (HRTEM; JEOL, JEMCXII; operating voltage 200 kV, Japan). TEM images were analyzed with Gatan Software for Inverse Fast Fourier Transform (IFFT) images. Thermogravimetric analysis was carried out by using a PerkinElmer 4000, USA thermal analyzer under nitrogen atmosphere at the temperature range of 25-800 °C (scanning rate 10 °C/min, gas flow rate 30 mL/min). Performance of the nanocomposite was studied by evaluating mechanical properties using a Universal Testing Machine (Zwick Z010, Germany equipped with a 10-kN load cell operating at crosshead speed of 50 mm/min).

FTIR spectrum of eggshell

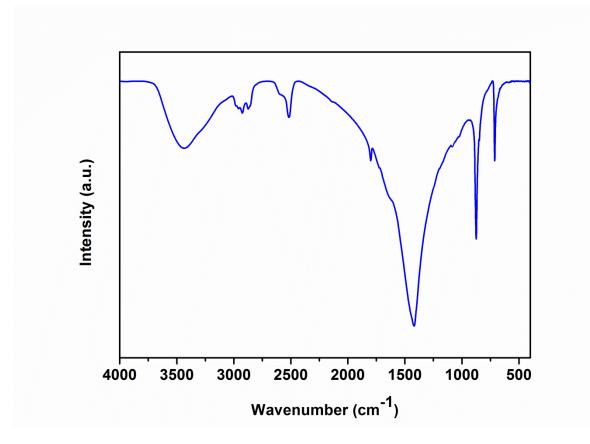


Fig. S1 FTIR spectrum of eggshell.

XRD pattern of carbon dot

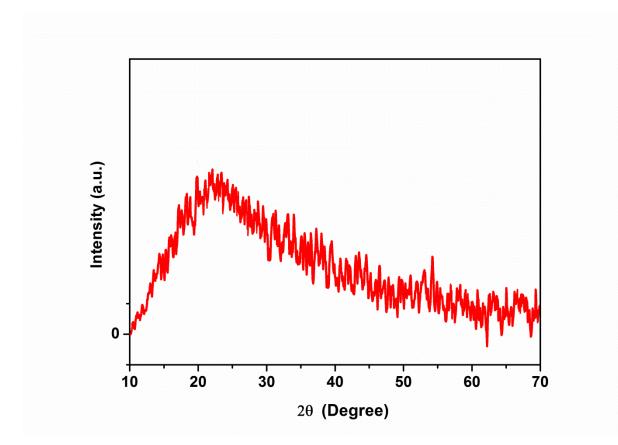


Fig. S2 XRD pattern of CD.

HRTEM of pristine carbon dot

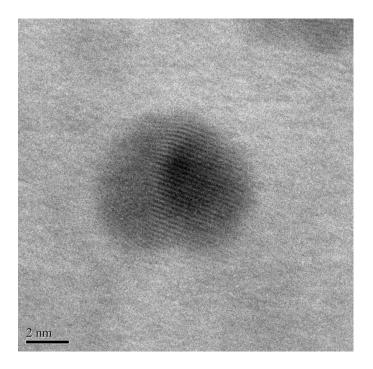


Fig. S3 HRTEM of CD.

TGA curves of the nanocomposite

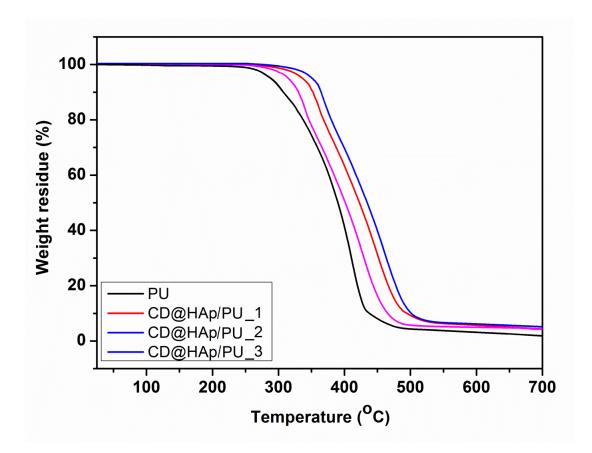


Fig. S4 TGA curves of CD@HAp/PUs.